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Application/Control No.	Applicant(s)/Patent under Reexamination
10/644,996	CHUN, CHANG-HYEN
Examiner	Art Unit
Pierre-Louis Desir	2617

SEARCHED				
Class	Subclass	Date	Examiner	
455	442	7/31/2007	PD	
455	436	7/31/2007	PD	
455	522	7/31/2007	PD	
455	434	7/31/2007	PD	
370	352	7/31/2007	PD	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
370	352	7/31/2007	PD
455	442	7/31/2007	PD
455	436	7/31/2007	PD
455/434,522		7/31/2007	PD

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